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INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)		Applicant: Toshitaka AGANO					
			Filing Date: April 2, 2001	Piling Date: Group: April 2, 2001			
		U.Ş. PAT	ENT DOCUMENTS				
Examiner Initial	Document Number	Date	Name	Class	Sub- Class	Filing Date (if appropriate)	
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-210 -	59-211263				class	Yes/No	
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